



BSI Standards Publication

Semiconductor devices — Mechanical and climatic test methods

Part 44: Neutron beam irradiated single
event effect (SEE) test method for
semiconductor devices

National foreword

This British Standard is the UK implementation of EN 60749-44:2016. It is identical to IEC 60749-44:2016.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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